

INFORMATION DISCLOSURE CITATION
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Docket Number (Optional)

Application Number

81190-2502 MRW

Applicant(s)

Larry Hryshko

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Filing Date

10530868 - GAU: 1657

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/A.W./		2002/064841	May 30/02	Mark A Reed et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
/A.W./		02/29402	Apr. 11/02	WO				
/A.W./		01/94939	Dec. 13/01	WO				
/A.W./		01/48475	July 5/01	WO				
/A.W./		02/64253	Aug 22/02	WO				

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

/A.W./		Mosbacher J et al, "Studying Membranes With Scanning Force Microscopy and Patch-Clamp Technique", Journal of Vacuum Science and Technology: Part B, American Institute of Physics, vol. 14, no. 2, March 1, 1996, pages 1449-1452.

EXAMINER /Amanda Wood/

DATE CONSIDERED 9/2008

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